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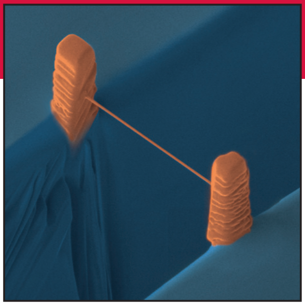
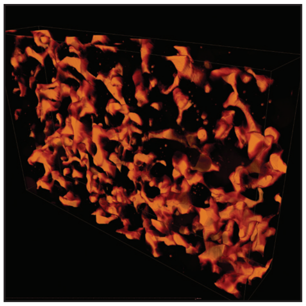
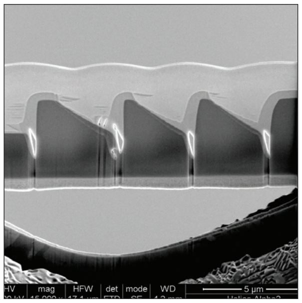


Platinum nanowire deposited and milled to about 50 nm diameter for use as a gas sensor *Courtesy of Peter Heard, Bristol University, United Kingdom*



Voltex visualization of porosities in a fuel cell electrode *Courtesy of Sabanci University, Turkey*



TEM lamella created to measure the amorphous damage created during FIB sample preparation *Image courtesy of D. Wall, FEI NanoPort, The Netherlands*

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